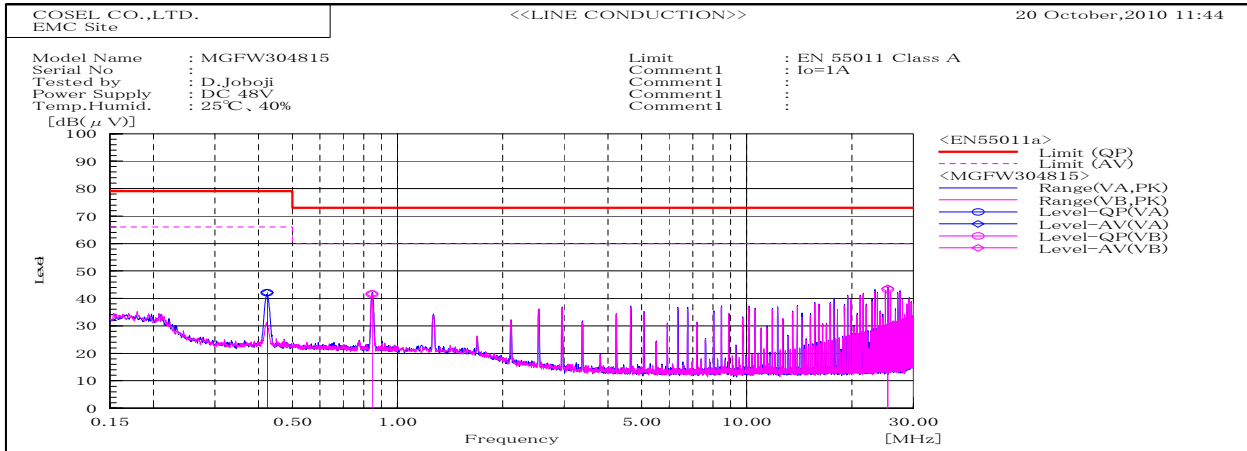
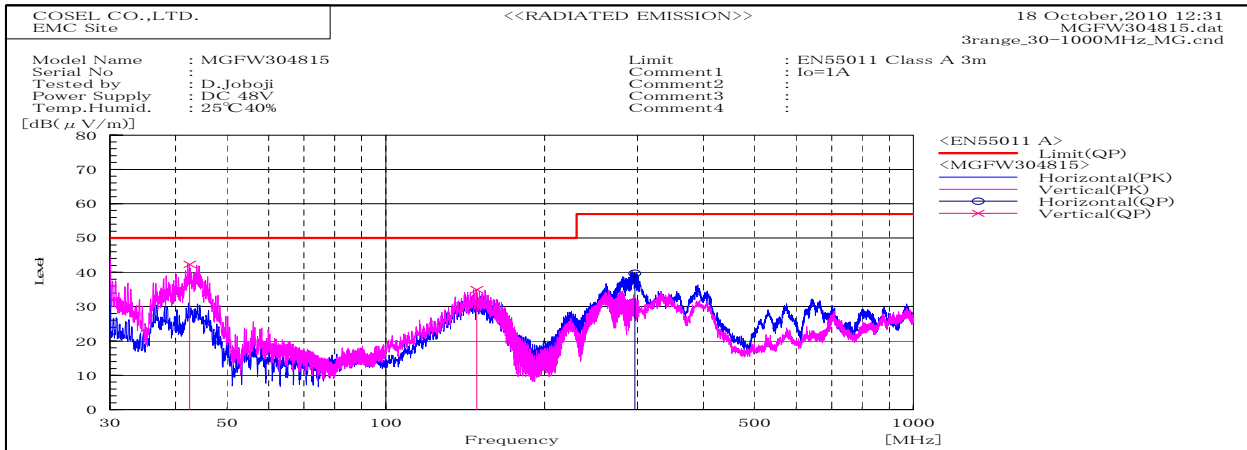


DATA SHEET		Date	20-Oct-10
Model	MGFW304815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.42306		VA	32	32	10.1	42.1	42.1	79	66	36.9	23.9	Pass	
0.84528		VB	31.6	31.7	10	41.6	41.7	73	60	31.4	18.3	Pass	
25.34345		VB	32.2	32.6	11.1	43.3	43.7	73	60	29.7	16.3	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV								
42.516	V	Stable	62.2	-19.9		42.3	50	7.7	Pass	102	255	
148.724	V	Stable	55.2	-20.2		35	50	15	Pass	157	58	
296.586	H	Stable	57.4	-17.7		39.7	57	17.3	Pass	103	175	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : MGFS3048□□/MGFW3048□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

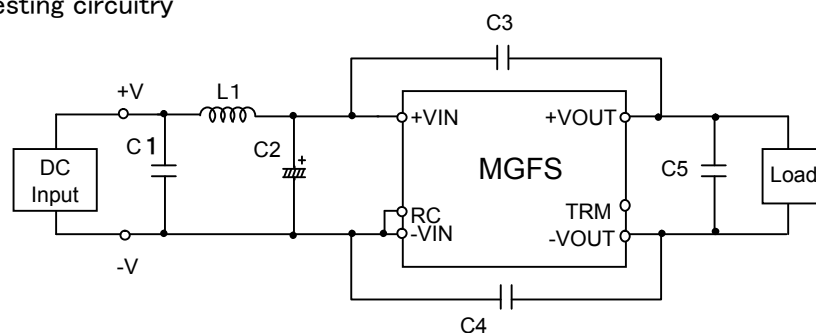


Fig.1 Testing circuitry 1

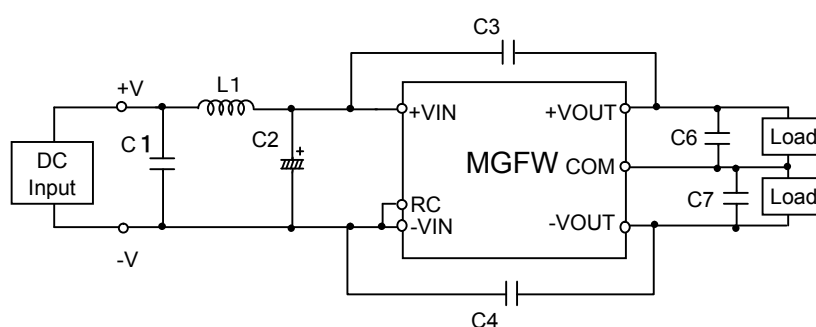


Fig.2 Testing circuitry 2

L1	: 4.7uH	CI8C-4R7	(KORIN ELECTRONICS)
C1	: 100V	2.2 μ F	Ceramic Capacitor
C2	: 80V	47 μ F	Electrolytic Capacitor
C3,C4	: 2kV	1000pF	Ceramic Capacitor
C5,C6,C7	: 25V	22 μ F	Ceramic Capacitor